

<b>Notice of References Cited</b>	Application/Control No. 10/617,106	Applicant(s)/Patent Under Reexamination AISO ET AL.	
	Examiner Devona E. Faulk	Art Unit 2615	Page 1 of 1

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*	B	US-6,985,595	01-2006	Kohyama et al.	381/119
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	M	US-			

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**NON-PATENT DOCUMENTS**

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